Session Program

23–25 May 2011

18th RD50 Workshop (Liverpool)

Defect and Material Characterization

Liverpool
University of Liverpool Conference Office The Foresight Centre 1 Brownlow Street

Monday 23 May

13:30

Defect and Material Characterization

Session | **Location:** Liverpool, University of Liverpool Conference Office The Foresight Centre 1 Brownlow Street | **Convener:** Mara Bruzzi

13:30–14:00

Some aspects of proton implantation and subsequent thermal annealing

Speaker
Dr Werner Schustereder

14:00–14:20

Deep level system Gaussian approximation according the extrinsic photoconductivity in irradiated Si diodes.

Speaker
Prof. Juozas Vaitkus

14:20–14:40

Carrier recombination and emission lifetimes in heavily irradiated pad–detectors and their impact on operational characteristics of pin diodes.

Speaker
Eugenijus Gaubas

14:40–15:00

Influence of material defects on the electrical properties of test-diodes for future cms tracking detectors

Speaker
alexandra junkes

15:00–15:20

Measurement of detrapping times in irradiated silicon detectors

Speaker
Gregor Kramberger

15:20–16:00

Coffee break

16:00–16:20

Study of Surface Radiation Damage in Silicon Sensors

Speaker
Mr Jiaguo Zhang

16:20–16:50

DMC - Discussion Session

Speaker
Mara Bruzzi

16:50